

<b>Notice of References Cited</b>		Application/Control No. 10/577,160	Applicant(s)/Patent Under Reexamination TSUBOYAMA ET AL.	
		Examiner MICHAEL WILSON	Art Unit 1794	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0019782 A1	09-2001	Igarashi et al.	428/690
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kukhto "Electroluminescence of thin films of organic compounds (Review)" Journal of Applied Spectroscopy, vol. 70, No. 2, 2003 pages 165-176.
	V	Skoog et al. "Principles of Instrumental Analysis" Saunders College, second edition, 1980, pages 280-289.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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